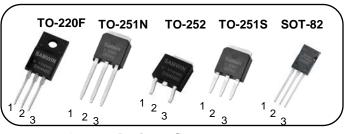


N-channel Enhanced modeTO-220F/TO-251N/TO-252/TO-251S/SOT-82 MOSFET

Features

- High ruggedness
- Low R_{DS(ON)} (Typ 2Ω)@V_{GS}=10V
 Low Gate Charge (Typ 18nC)
- Improved dv/dt Capability
- 100% Avalanche Tested
- Application: Charger, TV-POWER



1. Gate 2. Drain 3. Source

$R_{DS(ON)}$: 2 Ω

BV_{DSS}: 650V

: 4A

General Description

This power MOSFET is produced with advanced technology of SAMWIN. This technology enable the power MOSFET to have better characteristics, including fast switching time, low on resistance, low gate charge and especially excellent avalanche characteristics.





Order Codes

Item	Sales Type	Marking	Package	Packaging
1	SW F 4N65D	SW4N65D	TO-220F	TUBE
2	SW NI 4N65D	SW4N65D	TO-251N	TUBE
3	SW D 4N65D	SW4N65D	TO-252	REEL
4	SW SI 4N65D	SW4N65D	TO-251S	TUBE
5	SW S 4N65D	SW4N65D	SOT-82	TUBE

Absolute maximum ratings

	Parameter		Value					
Symbol			TO-220F	TO-251N	TO-252	TO-251S	SOT-82	Unit
V _{DSS}	Drain to source voltage		650					V
	Continuous drain current (@T _C =25°C)			4*				
l _D	Continuous drain current (@T _C =100°C)		2.5*				Α	
I _{DM}	Drain current pulsed (no	ote 1)			16			Α
V_{GS}	Gate to source voltage				±30			V
E _{AS}	Single pulsed avalanche energy (no	ote 2)			184			mJ
E _{AR}	Repetitive avalanche energy (no	ote 1)			15			mJ
dv/dt	Peak diode recovery dv/dt (note 3)		5				V/ns	
	Total power dissipation (@T _C =25°C)		23.3	157.1	144.4	157.1	95.4	W
P _D	Derating Factor above 25°C		0.19	1.26	1.15	1.26	0.76	W/°C
T_{STG},T_{J}	Operating junction temperature & storage temperature		-55 ~ + 150				°C	
T _L	Maximum lead temperature for soldering purpose, 1/8 from case for 5 seconds.		300			°C		

^{*.} Drain current is limited by junction temperature.

Thermal characteristics

Symbol			Value					
	Parameter	TO-220F	TO-251N	TO-252	TO-251S	SOT-82	Unit	
	R_{thjc}	Thermal resistance, Junction to case	5.36	0.80	0.87	0.80	1.31	°C/W
	R_{thja}	Thermal resistance, Junction to ambient	48.7	81.4	79.6	81.4	66.4	°C/W



Electrical characteristic ($T_C = 25^{\circ}C$ unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Off charact	teristics					
BV _{DSS}	Drain to source breakdown voltage	V _{GS} =0V, I _D =250uA	650			V
ΔBV _{DSS} /ΔT _J	Breakdown voltage temperature coefficient	I _D =250uA, referenced to 25°C		0.48		V/°C
,		V _{DS} =650V, V _{GS} =0V			1	uA
I _{DSS}	Drain to source leakage current	V _{DS} =520V, T _C =125°C			50	uA
	Gate to source leakage current, forward	V _{GS} =30V, V _{DS} =0V	(2)	100	nA
I _{GSS}	Gate to source leakage current, reverse	V _{GS} =-30V, V _{DS} =0V			-100	nA
On charact	teristics			!		
V _{GS(TH)}	Gate threshold voltage	$V_{DS}=V_{GS}$, $I_{D}=250uA$	2.5	-	4.5	V
R _{DS(ON)}	Drain to source on state resistance	V _{GS} =10V, I _D = 2A		2	2.6	Ω
Gfs	Forward transconductance	$V_{DS} = 30 \text{ V}, I_{D} = 2 \text{ A}$		3.8		S
Dynamic c	haracteristics		1			
C _{iss}	Input capacitance		7	531		
C _{oss}	Output capacitance	V _{GS} =0V, V _{DS} =25V, f=1MHz		60		pF
C _{rss}	Reverse transfer capacitance			50		
t _{d(on)}	Turn on delay time			11		
t _r	Rising time	V_{DS} =325V, V_{GS} =10V , I_{D} =4A		26		ns
$t_{d(off)}$	Turn off delay time	$R_G=25\Omega$ (note 4,5)		42		
t _f	Fall time			27		
Q_g	Total gate charge			18		
Q_{gs}	Gate-source charge	V_{DS} =520V, V_{GS} =10V, I_{D} =4A (note 4,5)		3		nC
Q_{gd}	Gate-drain charge	(9		

Source to drain diode ratings characteristics

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _S	Continuous source current	Integral reverse p-n Junction			4	Α
I _{SM}	Pulsed source current	diode in the MOSFET			16	Α
V _{SD}	Diode forward voltage drop.	I _S =4A, V _{GS} =0V			1.4	V
T _{rr}	Reverse recovery time	I _S =4A, V _{GS} =0V,		229		ns
Q _{rr}	Reverse recovery charge	dl _F /dt=100A/us		1.6		uC

X. Notes

- Repeatitive rating : pulse width limited by junction temperature. 1.
- L = 22.8mH, I_{AS} = 4A, V_{DD} = 50V, R_{G} =25Ω, Starting T_{J} = 25°C I_{SD} ≤ 4A, di/dt = 100A/us, V_{DD} ≤ BV_{DSS}, Staring T_{J} =25°C Pulse Test : Pulse Width ≤ 300us, duty cycle ≤ 2%. 2.
- 3.
- 4.
- Essentially independent of operating temperature.

Fig. 1. On-state characteristics

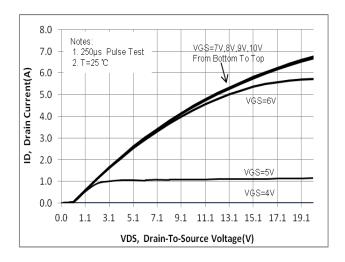


Fig. 3. Gate charge characteristics

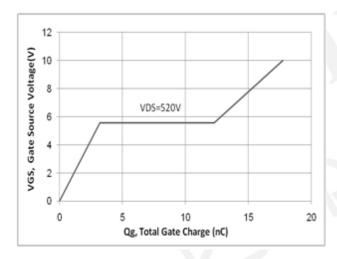


Fig 5. Breakdown Voltage Variation vs. Junction Temperature

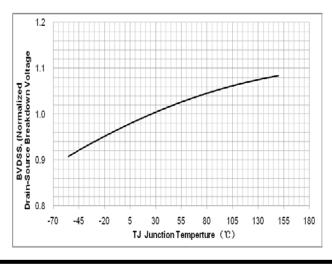


Fig. 2. On-resistance variation vs. drain current and gate voltage

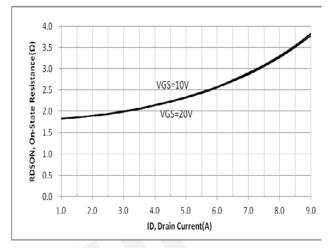


Fig. 4. On state current vs. diode forward voltage

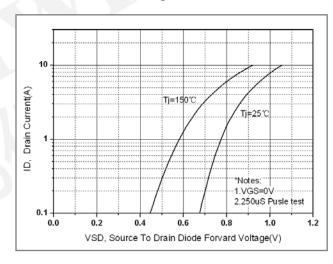


Fig. 6. On resistance variation vs. junction temperature

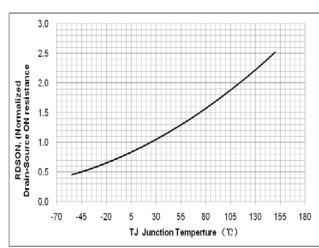


Fig. 7. Maximum safe operating area (TO-220F)

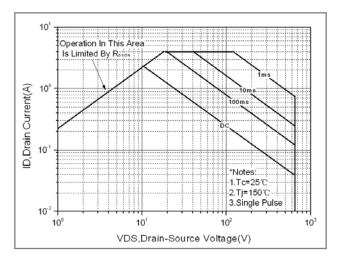


Fig. 9. Maximum safe operating area (TO-252)

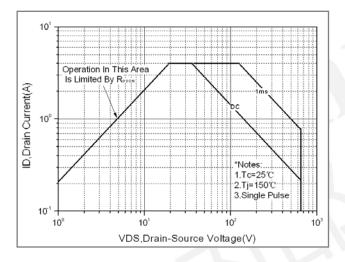


Fig. 8. Maximum safe operating area (TO-251N&TO-251S)

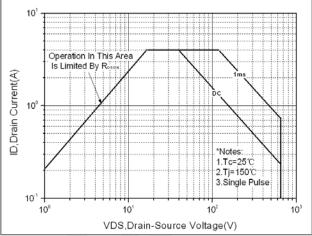


Fig. 10. Maximum safe operating area (SOT-82)

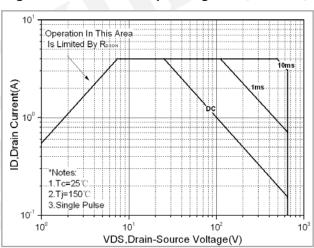


Fig. 11. Capacitance Characteristics

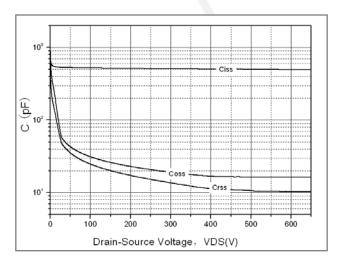


Fig. 12. Transient thermal response curve (TO-220F)

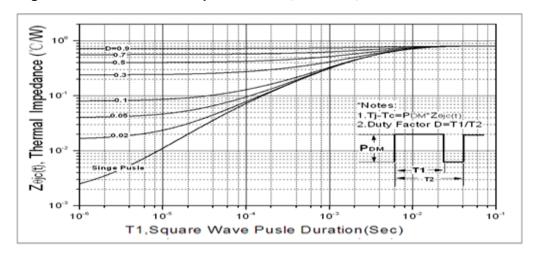


Fig. 13. Transient thermal response curve (TO-251N&TO-251S)

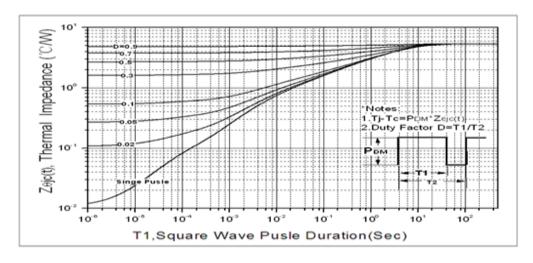


Fig. 14. Transient thermal response curve (TO-252)

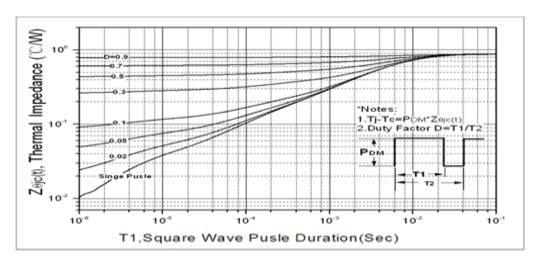


Fig. 15. Transient thermal response curve (SOT-82)

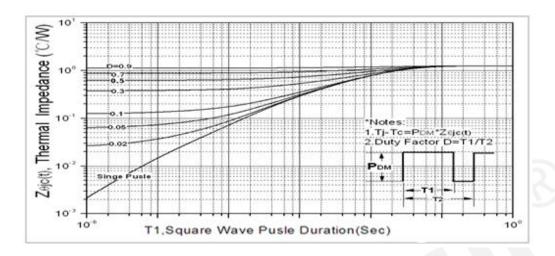


Fig. 16. Gate charge test circuit & waveform

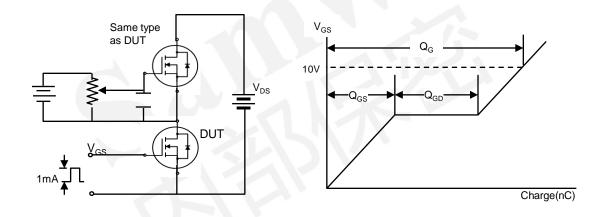


Fig. 17. Switching time test circuit & waveform

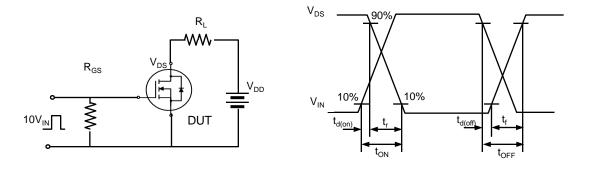


Fig. 18. Unclamped Inductive switching test circuit & waveform

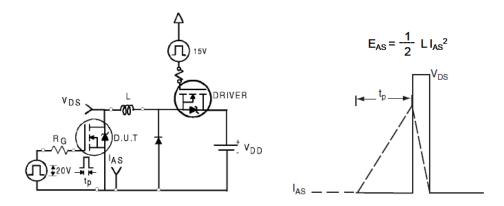
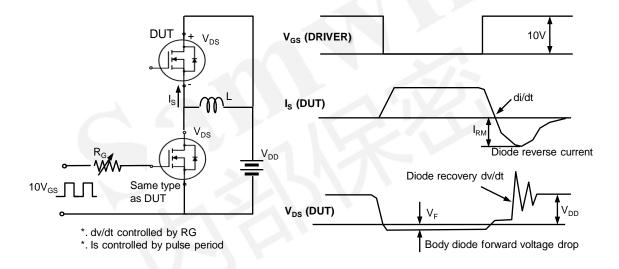


Fig. 19. Peak diode recovery dv/dt test circuit & waveform



DISCLAIMER

- * All the data & curve in this document was tested in XI'AN SEMIPOWER TESTING & APPLICATION CENTER.
- * This product has passed the PCT,TC,HTRB,HTGB,HAST,PC and Solderdunk reliability testing.
- * Qualification standards can also be found on the Web site (http://www.semipower.com.cn)
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* Suggestions for improvement are appreciated, Please send your suggestions to samwin@samwinsemi.com